Issue Classification

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CORTEN ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Art Unit

Wiehe, Nathan

3745

ORIGINAL				INTERNATIONAL CLASSIFICATION											
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Wiehe, Nathan William 11/14/2007 (Assistant Examiner) (Date)			Eden lle Look EDWARD K. LOOK						Total Claims Allowed:						
					SUP	SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700					O.G. Print Claim(s) O.G. Print Figu			O.G. Print Figure	
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